Se	earch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/055,442	HUNTLEY ET AL.
Examiner	Art Unit
Phuoc H. Nguyen	2143

	SEAD	CHED	
	JLAN	CITED	
Class	Subclass	Date	Examiner
	<u> </u>		
,			
		,	
			<u>.</u> .
			<u> </u>
		i	
			٠

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u> </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
See East Updated Search Report	9/21/2006	PN